PSMN3R5-30YL

N-channel TrenchMOS logic level FET

Rev. 01 — 14 October 2008

Preliminary data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in industrial and communications applications.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

1.3 Applications

- Class-D amplifiers
- DC-to-DC converters

- Motor control
- Server power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$		-	-	30	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u> ;	<u>[1]</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	74	W
Dynamic	characteristics						
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \frac{\text{Figure 14}}{\text{Figure 15}};$		-	5	-	nC
Static ch	aracteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 12}{}$		-	2.2	3.5	mΩ

^[1] Continuous current is limited by package.



2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	D
3	S	source		$G \bigoplus \overline{A}$
4	G	gate	q	<u> </u>
mb	D mounting base; connected to drain		1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN3R5-30YL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C		-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$		-	30	V
V_{GS}	gate-source voltage			-20	20	V
I_D	drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 1}};$	[1]	-	79	А
		V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ;	[1]	-	100	А
I _{DM}	peak drain current	$t_p \le 10 \mu\text{s}; \text{ pulsed}; T_{mb} = 25 ^{\circ}\text{C}; \text{ see } \underline{\text{Figure 3}}$		-	447	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	74	W
T _{stg}	storage temperature			-55	150	°C
Tj	junction temperature			-55	150	°C
Source-dra	ain diode					
Is	source current	T _{mb} = 25 °C;	<u>[1]</u>	-	100	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$		-	447	Α
Avalanche	ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 100 A; $V_{sup} \le$ 30 V; R_{GS} = 50 Ω; unclamped		-	54	mJ

^[1] Continuous current is limited by package.

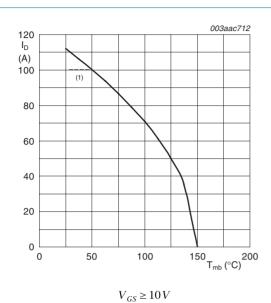
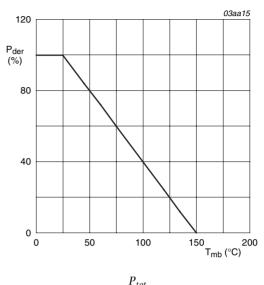


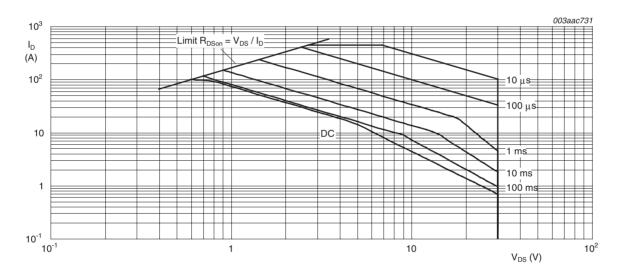
Fig 1. Continuous drain current as a function of mounting base temperature

(1) Capped at 100 A due to package.



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$ is single pulse (1) Capped at 100 A due to package.

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

N-channel TrenchMOS logic level FET

5. Thermal characteristics

Thermal characteristics Table 5.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.6	1.68	K/W

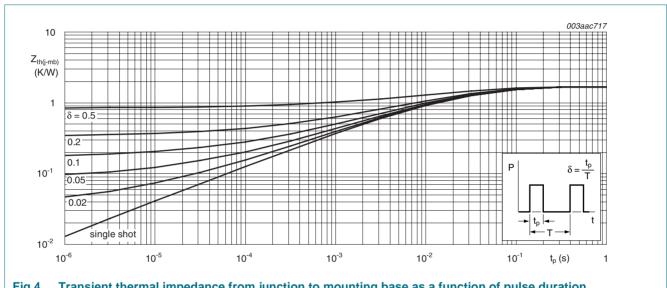


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
breakdown voltage		$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 ^{\circ}C$	27	-	-	V
V _{GS(th)} gate-source threshold voltage		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 10; see Figure 11	1.3	1.7	2.15	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 150 \text{ °C}$; see Figure 10	0.65	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = -55$ °C; see Figure 10	-	-	2.45	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nA
R _{DSon}	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}; \text{ see}$ <u>Figure 12</u>	-	3.18	5.6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C}; \text{ see}$ Figure 13	-	-	6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}; \text{ see}$ <u>Figure 12</u>	-	2.2	3.5	mΩ
R _G	gate resistance	f = 1 MHz	-	0.53	-	Ω
Dynamic	characteristics					
$Q_{G(tot)}$	total gate charge	$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see Figure 14; see Figure 15	-	19	-	nC
		I _D = 0 A; V _{DS} = 0 V; V _{GS} = 10 V	-	37	-	nC
		$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 10 \text{ V}$; see Figure 14; see Figure 15	-	41	-	nC
Q _{GS}	gate-source charge	$I_D = 10 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see	-	6	-	nC
Q _{GS(th)}	pre-threshold gate-source charge	Figure 14; see Figure 15	-	4	-	nC
Q _{GS(th-pl)}	post-threshold gate-source charge		-	2	-	nC
Q_{GD}	gate-drain charge		-	5	-	nC
$V_{GS(pl)}$	gate-source plateau voltage	V _{DS} = 12 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	2.4	-	V
C _{iss}	input capacitance	$V_{DS} = 12 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	2458	-	pF
C _{oss}	output capacitance	T _j = 25 °C; see <u>Figure 16</u>	-	532	-	pF
C _{rss}	reverse transfer capacitance		-	252	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 Ω ; V_{GS} = 4.5 V;	-	33	-	ns
t _r	rise time	$R_{G(ext)} = 4.7 \Omega$	-	50	-	ns
t _{d(off)}	turn-off delay time		-	45	-	ns
t _f	fall time		-	18	-	ns

PSMN3R5-30YL_1

5 of 13

N-channel TrenchMOS logic level FET

Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-drain diode						
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 17	-	0.88	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	[tbd]	37	ns
Q_r	recovered charge	$V_{DS} = 20 \text{ V}$	-	[tbd]	31	nC

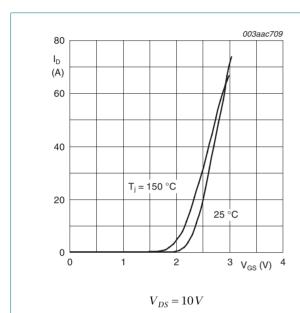


Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values

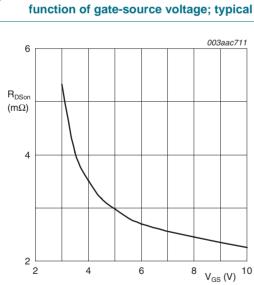


Fig 7. Drain-source on-state resistance as a function of gate-source voltage; typical values

 $T_i = 25 \,^{\circ}C; I_D = 15A$

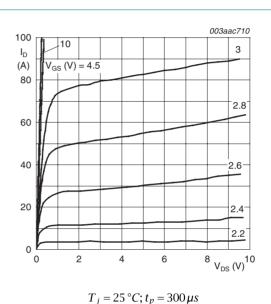


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

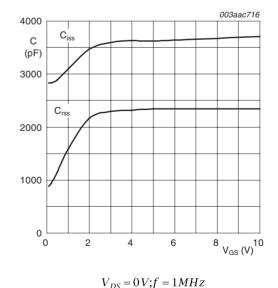
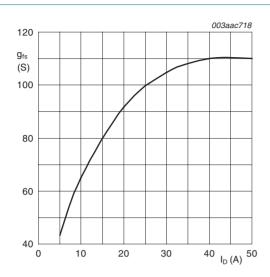


Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



 $T_{j} = 25 \,^{\circ}C; V_{DS} = 15 \, V$

Fig 9. Forward transconductance as a function of drain current; typical values

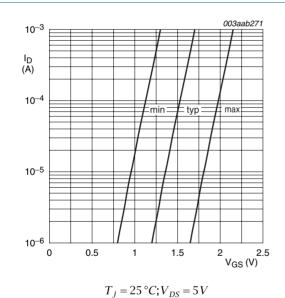
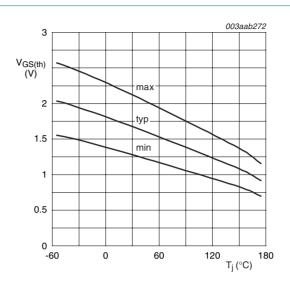
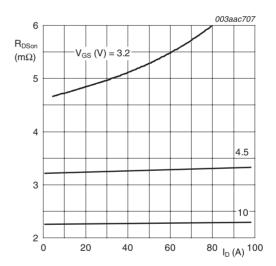


Fig 11. Sub-threshold drain current as a function of gate-source voltage



 $I_D = 1 \, mA; V_{DS} = V_{GS}$

Fig 10. Gate-source threshold voltage as a function of junction temperature



$$T_j = 25 \,{}^{\circ}C; t_p = 300 \,\mu s$$

Fig 12. Drain-source on-state resistance as a function of drain current; typical values

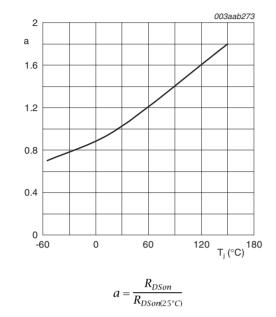


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

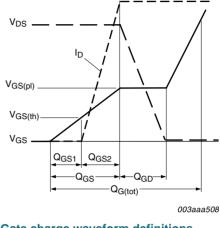


Fig 14. Gate charge waveform definitions

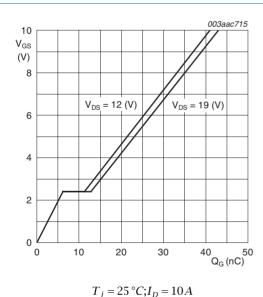
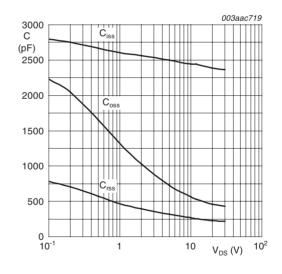


Fig 15. Gate-source voltage as a function of gate

charge; typical values



$$V_{GS} = 0V; f = 1MHz$$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

Preliminary data sheet

9 of 13

N-channel TrenchMOS logic level FET

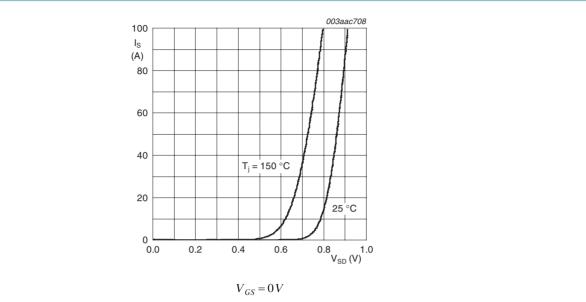
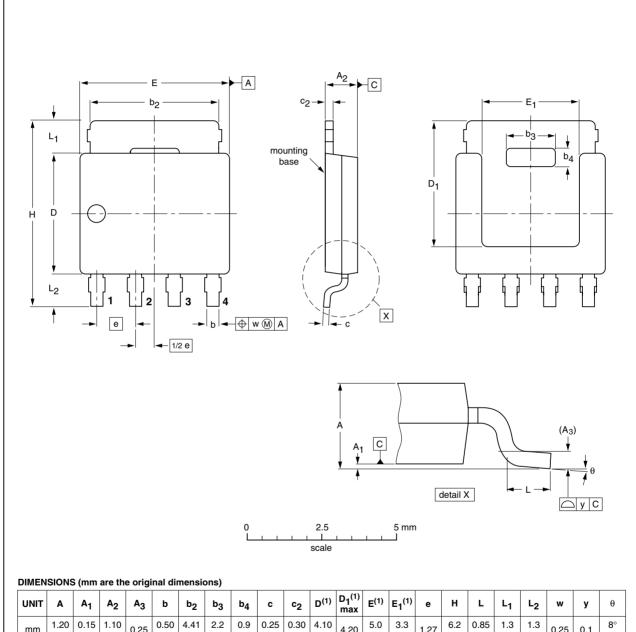


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



	UNIT	A	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
	mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	l .	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8° 0°
L		1.01	0.00	0.00		0.00	0.02	2.0	0.7	0.10	0.2 1	0.00		1.0	0.1		0.0	0.10	0.0	0.0			·

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT669		MO-235				04-10-13 06-03-16

Fig 18. Package outline SOT669 (LFPAK)

PSMN3R5-30YL

11 of 13

N-channel TrenchMOS logic level FET

Revision history

Table 7. **Revision history**

Preliminary data sheet

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN3R5-30YL_1	20081014	Preliminary data sheet	-	-

N-channel TrenchMOS logic level FET

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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PSMN3R5-30YL

N-channel TrenchMOS logic level FET

11. Contents

1	Product profile
1.1	General description
1.2	Features and benefits1
1.3	Applications
1.4	Quick reference data1
2	Pinning information2
3	Ordering information2
4	Limiting values2
5	Thermal characteristics4
6	Characteristics5
7	Package outline
8	Revision history11
9	Legal information12
9.1	Data sheet status
9.2	Definitions
9.3	Disclaimers
9.4	Trademarks12
10	Contact information12

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